

Search Notes

Application/Control No.

10/069,595

Examiner

Mark K. Han

Applicant(s)/Patent under
Reexamination

AHNBLAD ET AL.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner
604	93.01	8/21/2006	<i>mjh</i>
	94.01		
	181		
	183		
	187		
	212		
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	514		
606	523		
606	199		
128	200.14		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search	8/21/2006	<i>mjh</i>